1

8192 x 8-BIT LINE MEMORY

DESCRIPTION

The M66282FP is high speed line memory that uses high performance silicon gate CMOS process technology and adopts the FIFO (First In First Out) structure consisting of 8192 words x 8 bits.

The M66282FP, performing reading and writing operations at different cycles independently and asynchronously, is optimal for buffer memory to be used between equipment of different data processing speeds.

FEATURES

- Memory configuration
- 8192 words x 8 bits (dynamic memory) 25 ns (Min.)
- High speed cycle High speed access 18 ns (Max.)
- Output hold
- 3 ns (Min.) • Reading and writing operations can be completely carried out independently and asynchronously.
- · Variable length delay bit
- Input/output
- Output
- TTL direct connection allowable 3 states

APPLICATION

• Digital copying machine, laser beam printer, high speed facsimile, etc.

FUNCTION

When write enable input WEB is set to "L", the contents of data inputs D0 to D7 are read in synchronization with a rising edge of write lock input WCK to perform writing operation. When this is the case, the write address counter is also incremented simultaneously. When WEB is set to "H", the writing operation is inhibited and the write address counter stops.

When write reset input WRESB is set to "L", the write address counter is initialized.

When read enable input REB is set to "L", the contents of memory are output to data outputs Q0 to Q7 in synchronization with a rising edge of read clock input RCK to perform reading operation. When this is the case, the read address counter is incremented simultaneously.

When REB is set to "H", the reading operation is inhibited and the read address counter stops. The outputs are placed in a high impedance state.

When read reset input RRESB is set to "L", the read address counter is initialized.



8192 x 8-BIT LINE MEMORY



8192 x 8-BIT LINE MEMORY

ABSOLUTE MAXIMUM RATINGS (Ta=0 - 70 °C unless otherwise noted)

Symbol	Parameter	Conditions	Ratings	Unit
Vcc	Supply voltage		-0.3 - +4.6	V
Vi	Input voltage	Value based on the GND pin	-0.3 - Vcc+0.3	V
Vo	Output voltage		-0.3 - Vcc+0.3	V
Pd	Power dispersion		300	mW
Tstg	Storage temperature		-55 — 150	°C

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter		Linit		
		Min.	Тур.	Max.	Unit
Vcc	Supply voltage	2.7	3.15	3.6	V
GND	Supply voltage		0		V
Topr	Operating temperature	0		70	°C

ELECTRICAL CHARACTERISTICS (Ta=0 - 70 °C, Vcc=2.7 - 3.6V, GND=0V unless otherwise noted)

0h.al	Deveryoter	Conditions		Limits			11.2
Symbol	Parameter			Min.	Тур.	Max.	Unit
Viн	High-level input voltage			2.0			V
VIL	Low-level input voltage					0.8	V
Vон	High-level output voltage	IOH = -4mA		Vcc-0.4			V
Vol	Low-level output voltage	IoL = 4mA				0.4	V
Ін	High-level input current	VI = VCC	WEB, WRESB, WCK, REB, RRESB, RCK, D0 – D7			1.0	μA
lı∟	Low-level input current	Vi = GND	WEB, WRESB, WCK, REB, RRESB, RCK, D0 – D7			-1.0	μA
Іоzн	Off-state high-level output current	Vo = Vcc				5.0	μA
Iozl	Off-state low-level output current	Vo = GND				-5.0	μΑ
lcc	Average supply current during operation	VI = Vcc, GND, output open twck, trck = 25ns				70	mA
С	Input capacitance	f = 1MHz				10	pF
Со	Off-time output capacitance	f = 1MHz				15	pF

8192 x 8-BIT LINE MEMORY

SWITCHING CHARACTERISTICS (Ta=0 - 70 °C, Vcc=2.7 - 3.6V, GND=0V unless otherwise noted)

Symbol	Parameter	Limits			Linit
		Min.	Тур.	Max.	Unit
tAC	Access time			18	ns
toн	Output hold time	3			ns
t OEN	Output enable time	3		18	ns
todis	Output disable time	3		18	ns

TIMING REQUIREMENTS (Ta=0 - 70 °C, Vcc=2.7 - 3.6V, GND=0V unless otherwise noted)

Symbol	Parameter		Limits		
		Min.	Тур.	Max.	Unit
twcĸ	Write clock (WCK) cycle	25			ns
twcкн	Write clock (WCK) "H" pulse width	11			ns
t WCKL	Write clock (WCK) "L" pulse width	11			ns
t RCK	Read clock (RCK) cycle	25			ns
trcкн	Read clock (RCK) "H" pulse width	11			ns
t RCKL	Read clock (RCK) "L" pulse width	11			ns
tDS	Input data set up time for WCK	7			ns
tDH	Input data hold time for WCK	3			ns
tRESS	Reset set up time for WCK/RCK	7			ns
t RESH	Reset hold time for WCK/RCK	3			ns
t NRESS	Reset non-selection set up time for WCK/RCK	7			ns
t NRESH	Reset non-selection hold time for WCK/RCK	3			ns
twes	WEB set up time for WCK	7			ns
twen	WEB hold time for WCK	3			ns
t NWES	WEB non-selection set up time for WCK	7			ns
t NWEH	WEB non-selection hold time for WCK	3			ns
tres	REB set up time for RCK	7			ns
t REH	REB hold time for RCK	3			ns
t NRES	REB non-selection set up time for RCK	7			ns
t NREH	REB non-selection hold time for RCK	3			ns
tr, tf	Input pulse up/down time			20	ns
tн	Data hold time (Note 1)			20	ms

Note 1: For 1 line access, the following conditions must be satisfied:

WEB high-level period \leq 20 ms - 8192 • tWCK - WRESB low-level period

REB high-level period ≤ 20 ms - 8192 • tRCK - RRESB low-level period

2: Perform reset operation after turning on power supply.

4

8192 x 8-BIT LINE MEMORY



tODIS and tOEN measurement condition

SWITCHING CHARACTERISTICS MEASUREMENT CIRCUIT



8192 x 8-BIT LINE MEMORY

OPERATION TIMING

• Write cycle



WRESB = "H"

• Write reset cycle



WEB = "L"

7

8192 x 8-BIT LINE MEMORY



• Matters that needs attetion when WCK stops

Input data of n cycle is read at the rising edge after WCK of n cycle and writing operation starts in the WCK low-level period of n+1 cycle. The writing operation is complete at the falling edge after n+1 cycle.

To stop reading write data at n cycle, enter WCK before the rising edge after n+1 cycle.

When the cycle next to n cycle is a disable cycle, WCK for a cycle requires to be entered after the disable cycle as well.

8192 x 8-BIT LINE MEMORY

Read cycle





• Read reset cycle



8192 x 8-BIT LINE MEMORY

VARIABLE LENGTH DELAY BIT

• 1 line (8192 bits) delay

Input data can be written at the rising edge of WCK after write cycle and output data is read at the rising edge of RCK before read cycle to easily make 1 line delay.



• n-bit delay bit

(Reset at cycles according to the delay length)



9

8192 x 8-BIT LINE MEMORY

• n-bit delay 2

(Slides input timings of WRESB and RRESB at cycles according to the delay length.)



• n-bit delay 3

(Slides address by disabling REB in the period according to the delay length.)



• Reading shortest n-cycle write data "n"

(Reading side n-1 cycle starts after the end of writing side n-1 cycle.)

When the reading side n-1 cycle starts before the end of the writing side n+1 cycle, output Qn of n cycle is made invalid. In the following diagram, reading operation of n-1 cycle is invalid.



Reading longest n-cycle write data "n": 1 line delay

(When writing side n-cycle <2>* starts, reading side n cycle <1>* then starts.)

Output Qn of n cycle <1>* can be read until the start of reading side n cycle <1> and the start of writing side n cycle <2>* overlap each other.



<0>*, <1>* and <2>* indicate value of lines.

8192 x 8-BIT LINE MEMORY

APPLICATION EXAMPLE



Sub Scan Resolution Compensation Circuit with Laplacean Filter